



FPD Materials and Components Japan TC Chapter and FPD Metrology Japan TC Chapter Joint Meeting Meeting Summary and Minutes

SEMI Japan Standards Spring 2017 Meetings

Friday, April 7, 2017, 15:00-17:00

SEMI Japan, Tokyo, Japan

TC Chapter Announcements

FPD Materials & Components Japan TC Chapter:

SEMI Japan Standards Fall 2017 Meetings

Friday, September 15, 2017, 15:00-17:00

SEMI Japan, Tokyo, Japan

FPD Metrology Japan TC Chapter:

SEMI Japan Standards Fall 2017 Meetings

Friday, September 15, 2017, 15:00-17:00

SEMI Japan, Tokyo, Japan

Table 1 Meeting Attendees

Co-Chairs of FPD M&C Committee: Tadahiro Furukawa (Yamagata University), Yoshi Shibahara (Fujifilm)

Co-Chairs of FPD Metrology Committee: Ryoichi Watanabe (Japan Display), Akira Kawaguchi (Otsuka Electronics)

SEMI Staff: Naoko Tejima (SEMI Japan)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
ITRI	Bao-Jen Pong	Andy			
Sumitomo Bakelite	Eguchi	Toshimasa	Nitto Denko	Tatsumi	Motoshige
Yamagata University	Furukawa	Tadahiro	Sony	Tomioka	Satoshi
Fujifilm	Shibahara	Yoshi	Japan Display	Watanabe	Ryoichi
Teijin	Ito	Haruhiko	SEMI Japan	Tejima	Naoko
Otsuka Electronics	Kawaguchi	Akira			

* alphabetical order by last name

Table 2 Leadership Changes

FPD M&C Japan TC Chapter

<i>Group</i>	<i>Previous Leader</i>	<i>New Leader</i>
<i>Polarizing Film Task Force Co-leaders</i>	- Toshihito Otsuka (Sanritz) - Yoshi Shibahara (Fujifilm) - Motoshige Tatsumi (Nitto Denko)	- Yoshi Shibahara (Fujifilm) - Motoshige Tatsumi (Nitto Denko)

FPD Metrology Japan TC Chapter

None.

Table 3 Ballot Results

Passed ballots and line items will be forwarded to the ISC Audit & Review Subcommittee for procedural review.

Failed ballots and line items were returned to the originating task forces for re-work and re-balloting.

FPD M&C Japan TC Chapter

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
6103	Line Item Revision to SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter with Title Change to: Test Method for Depolarization Effect of FPD Color Filter	Failed

FPD Metrology Japan TC Chapter

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
6101	Line Item Revision to SEMI D31-0213, with title change from “Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection” to “Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection”	Passed as balloted

Table 4 Authorized Activities

FPD M&C Japan TC Chapter

None.

FPD Metrology Japan TC Chapter

None.

NOTE 1: SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 5 Authorized Ballots

FPD M&C Japan TC Chapter

<i>Doc.#</i>	<i>When</i>	<i>SC/TF/WG</i>	<i>Details</i>
5977	Cycle 5, 2017	Flexible Display TF	New Standard, Test Method of Water Vapor Barrier Property for Plastic Films with High Barrier for Electronic Devices

FPD Metrology Japan TC Chapter

None.

Table 6 New Action Items

FPD M&C Japan TC Chapter

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPD M&C 170407-01	FPD Color Filter TF	To rework for the Document 6103 (Line Item Revision to SEMI D63-0811)
FPD M&C 170407-02	SEMI Staff	To request GCS review of revision SNARF of Doc.6104, SEMI D60-0710: Test Method of Surface Scratch Resistance for FPD Polarizing Film and Its Materials, with title change to: Test Method of Surface Scratch Resistance for FPD Polarizing Film and Cover Plastics for Mobile Display, after 2-weeks review by TC members.
FPD M&C 170407-03	SEMI Staff	To submit Doc. 5977, New Standard, Test Method of Water Vapor Barrier Property for Plastic Films with High Barrier for Electronic Devices, for Cycle 5, 2017

FPD Metrology Japan TC Chapter

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPD Met 170407-01	SEMI Staff	To forward adjudication result of Doc.6101, Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, to the ISC A&R Subcommittee for procedural review

Table 7 Previous Meeting Action Items

FPD M&C Japan TC Chapter

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPD M&C 160701-05	SEMI Staff	To contact Mr. Otsuka and ask him his intention, and request him to send his replacement, if he will decline the co-leader position. ... Closed
FPD M&C 161109-01	SEMI Staff	To submit <i>Line Item Revision to SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter with Title Change to: Test Method for Depolarization Effect of FPD Color Filter</i> for Cycle 9, 2016. ... Closed
FPD M&C 161109-02	SEMI Staff	To check if the SNARF should be resubmitted, when Scope will be widen and Title will be changed (Doc.#6014). ... Closed

FPD Metrology Japan TC Chapter

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPD Met 161109-01	SEMI Staff	To submit <i>Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection.</i> for Cycle 9, 2016. ->CLOSE

[Common Part 1]

1 Welcome, Reminders, and Introductions

Tadahiro Furukawa, committee co-chair, called the meeting to order at 15:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

2 SEMI Staff Report

Naoko Tejima gave the SEMI staff report. This report included SEMI Global 2017 Calendar of Events, Global Standards Meeting Schedule, 2017 Critical Dates for SEMI Standards Ballots, A&R Ballot Review, SEMI Standards Publication, PPT Template Updates, JRSC Organization Chart, SEMI Tsushin, Global Staff Assignment and Contact Information.

Attachment: 01_SEMI_Staff_Report_170407

3 Liaison Reports

3.1 FPD Metrology Korea TC Chapter

Naoko Tejima reported for the FPD Metrology Korea TC Chapter. This report included Leadership, Organization Chart, Meeting Information, Major Updates, Subcommittee/TF/WG Updates and Contact Information

Attachment: 02_Korea_FPD_Liaison_Report_170407

3.2 FPD Metrology Taiwan TC Chapter

Naoko Tejima reported for the FPD Metrology Taiwan TC Chapter. This report included Leadership, Organization Chart, Meeting Information, Ballot Result, FPD Metrology Committee Highlights and Contact Information.

Attachment: 03_Taiwan_Liaison_Report_170407

[FPD Materials & Components Japan TC Chapter Part]

4 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

It was pointed followings:

- “To submit ballot of Line Item Revision to SEMI D63-0811, ...Motion passed.” should be deleted.

Motion: To approve the minutes of the previous meeting as written after the above a point is corrected.

By / 2nd: Yoshi Shibahara (Fujifilm) / Motoshige Tatsumi (Nitto Denko)

Discussion: None

Vote: 8 in favor and 0 opposed. **Motion passed.**

Attachment: 04_JA_FPD_M+C_Previous_Mtg_Minutes_170407

5 Ballot Review

5.1 *Doc.6103, Line Item Revision to SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter with Title Change to: Test Method for Depolarization Effect of FPD Color Filter*

This document failed committee review.

Action Item: FPD Color Filter Task Force to rework for the Document 6103

Attachment: 05_6103_Ballot_Report_170407

6 Task Force Reports

6.1 Polarizing Film Task Force

Yoshi Shibahara reported as follows:

- *Regarding Doc. 6014 Revision to SEMI D60-0710: Test Method of Surface Scratch Resistance for FPD Polarizing Film and Its Materials, the Scope will be widen and Title will be changed. Revision SNARF will be reviewed and will get the approval by the GCS.*

Action Item: SEMI to request GCS review of revision SNARF of *Doc.6014, SEMI D60-0710: Test Method of Surface Scratch Resistance for FPD Polarizing Film and Its Materials, with title change to: Test Method of Surface Scratch Resistance for FPD Polarizing Film and Cover Plastics for Mobile Display*, after 2-weeks review by TC members.

Attachment: 06_Revised_SNARF_for_revision_of_D60_170407

Motoshige Tatsumi reported as follows:

- Working for the 1st draft of *Doc. 6006, New Standard: Test method for measurements of dimension of films for FPD – contour matching method.*

6.2 Flexible Display Task Force

Tadahiro Furukawa reported for the Flexible Display Task Force.

- Drafting *Doc. 5977, New Standard, Test Method of Water Vapor Barrier Property for Plastic Films with High Barrier for Electronic Devices.*

Motion: To submit *Doc. 5977, New Standard, Test Method of Water Vapor Barrier Property for Plastic Films with High Barrier for Electronic Devices* for Cycle 5, 2017.

By / 2nd: Toshimasa Eguchi (Sumitomo Bakelite) / Haruhiko Ito (Teijin)

Discussion: None.

Vote: 6 in favor and 0 opposed. **Motion passed.**

6.3 FPD Color Filter Task Force

Tadahiro Furukawa reported for the FPD Color Filter Task Force. Of note:

- *Doc.6103, Line Item Revision to SEMI D63-0811, Measurement Method for Depolarization Effect of FPD Color Filter with Title Change to: Test Method for Depolarization Effect of FPD Color Filter*, failed committee review as previously discussed. (See 5).

6.4 FPD Mask Task Force

No Report was provided.

7 Old Business

7.1 Previous Meeting Action Items

Naoko Tejima reviewed the old action items. These can be found in the Old Action Items table at the beginning of these minutes.

8 New Business

None.

[FPD Metrology Japan TC Chapter Part]

9 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: To approve the minutes of the previous meeting as written.

By / 2nd: Tadahiro Fufukawa (Yamagata University) / Akira Kawaguchi (Otsuka Electronics)

Discussion: None

Vote: 6 in favor and 0 opposed. **Motion passed.**

Attachment: 04_JA_FPD_M+C_Previous_Mtg_Minutes_170407

10 Ballot Review

10.1 *Doc.6101, Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection*

This document passed committee review and will be forwarded to the ISC A&R SC for procedural review.

Action Item: SEMI staff to forward adjudication result of Doc.6101 to the ISC A&R Subcommittee for procedural review.

Attachment: 07_6101_Ballot_Report_170407

11 Task Force Reports

11.1 *D31 Revision Task Force*

Ryoichi Watanabe, Co-leaders of FPD Metrology Japan TC Chapter reported for the D31 Revision Task Force. Of note:

- *Doc.6101, Line Item Revision of SEMI D31-0914, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection, with title change to: Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection*, passed committee review as previously discussed. (See 5).

12 Old Business

12.1 *Previous Meeting Action Items*

Naoko Tejima reviewed the old action items. These can be found in the Old Action Items table at the beginning of these minutes.

13 New Business

None.

[Common Part 2]

14 Action Item Review

14.1 *New Action Items*

Naoko Tejima reviewed the new action items. These can be found in the New Action Items table at the beginning of these minutes.

15 Next Meeting and Adjournment

The next meeting of the FPD Materials and Components Japan TC Chapter is scheduled for Friday, September 15, 2017, 15:00-17:00, SEMI Japan, Tokyo, Japan.

The next meeting of the FPD Metrology Japan TC Chapter is scheduled for Friday, September 15, 2017, 15:00-17:00, SEMI Japan, Tokyo, Japan.

See <http://www.semi.org/en/events> for the current list of meeting schedules.

Having no further business, a motion was made to adjourn. Adjournment was at 17:00.



Respectfully submitted by:
Naoko Tejima
Manager, Standards
SEMI Japan
Phone: +81.3.3222.5804
Email: ntejima@semi.org

Minutes tentatively approved by:

Tadahiro Furukawa (Yamagata University), Co-chair of FPD Materials & Components Japan TC Chapter	** **, 2017
Yoshi Shibahara (Fujifilm) , Co-chair of FPD Materials & Components Japan TC Chapter	** **, 2017
Ryoichi Watanabe (Japan Display), Co-chair of FPD Metrology Japan TC Chapter	** **, 2017
Akira Kawaguchi (Otsuka Electronics) , Co-chair of FPD Metrology Japan TC Chapter	** **, 2017

Table 8 Index of Available Attachments #1

#	<i>Title</i>
1	SEMI_Staff_Report_170407
2	Korea_FPD_Liaison_Report_170407
3	Taiwan_Liaison_Report_170407
4	JA_FPD_M+C_Met_Previous_Mtg_Minutes_170407
5	6103_Ballot_Report_170407
6	Revised_SNARF_for_revision_of_D60_170407
7	6101_Ballot_Report_170407

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.